Form PTO 1449		U.S. DEDARTMENT	DE COMMERCE	ATTY DOCKET NO.	SERIAL NO.			
Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			248212US2	New Application				
				APPLICANT				
LIST OF	REFEF	RENCES CITED BY AP	PLICANT	Masao MIYAMURA				
				FILING DATE		GROUP 1700		
				Herewith	1709			
U.S. PATENT DOCUMENTS								
EXAMINER		DOCUMENT	DATE	NAME	CLASS	SUB		LING DATE
INITIAL		NUMBER			204	CLASS	298.03	
/MB/	AA	5,169,509	12/08/92	Rudolf LATZ, et al.	204	298.0		
/MB/ /MB/	AB	5,082,546	01/21/92	Joachim SZCZYRBOWSKI, et al.	427	535	•	
	AC	6,103,320	08/15/00	Shigeharu MATSUMOTO, et al.	204	192.1	2	
/MB/	AD	4,851,095	07/25/89	Michael A. SCOBEY, et al.	203	172.1		
	AF							
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	AK		<del> </del>					
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	AM				<u> </u>			•
	AN		<del> </del>				<b>.</b>	
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
/MB/	AO	8-511830	12/10/96	Japan				x
/MB/	AP	11-256327	09/21/99	Japan				×
/MB/	AQ	2-269514	11/02/90	Japan (with English Abstract, Corresponding U.S. Patent 5,082,546)				x
/MB/	AR	11-279758	10/12/99	Japan (with English Abstract, Corresponding U.S. Patent 6,103,320)				×
/MB/	AS	4-325680	11/16/92	Japan (with English Abstract, Correspo Patent 5,169,509)			×	
/MB/	АТ	3-229870	10/11/91	Japan (with English Abstract, Corresponding U.S. Patent 4,851,095)				x
	AU				<del> </del>			
	AV	<u></u>	<u> </u>			<u> </u>		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
/MB/ R. LAIRD, et al., "Cosputtered Films of Mixed TiO <sub>2</sub> /SiO <sub>2</sub> ", J. VAC. SCI. TECHNOL., Vol. A10, No. 4, July/August 1992, p. 1908-1912								
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Examiner	<u> </u>	/Michael Band		· · · · · · · · · · · · · · · · · · ·	Additional References sheet(s) attached  Date Considered 04/19/2007			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in								
conformance and not considered. Include copy of this form with next communication to applicant.								